ECET 102/CPET101

Lab 5 Parallel Circuit Lab

By Prof. Paul I. Lin

Required Devices & Equipment:

Resistors: $820\Omega \times 1$, $1.2k\Omega \times 2$

Bread board x 1 with wires, wire strippers and cutters

Variable Power Supply x 1 Digital Multimeter (DMM) x 1

Objectives:

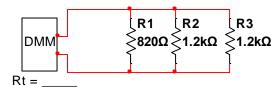
- 1. Learn parallel resistor circuits and measurement.
- 2. Learn to use the circuit design and simulation program, Multisim, for circuit analysis.
- 3. Verify Kirchoff's Current Law (KCL)

Procedure:

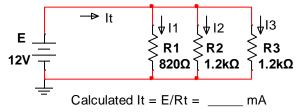
Part 1. Three Resistor in Parallel and Current Measurement

a) Use a DMM to measure the resistance of the three resistors R1, R2, and R2 and record the values:

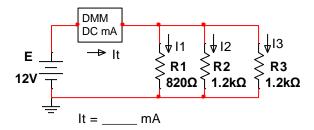
- b) Manually calculate the total circuit resistance Rt = $1/(1/R1 + 1/R2 + 1/R3) = \Omega$.
- c) Set up the circuit as shown in Figure 1 using the three resistors, then use the DMM (set to Ohm measurement) to measure the total parallel resistance $Rt = \underline{\qquad} \Omega$.



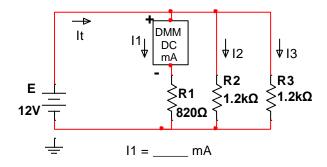
- d) Compare the results obtained from (a) and (b).
- e) Calculate the total circuit current It = ____ mA, and record the calculated It in Table 1.



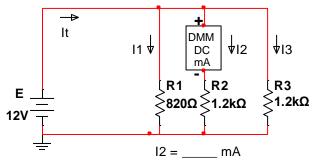
f) Connect the variable power supply, set to 12V. Use the DMM (set to DC I measurement) to measure the current It = _____ mA, and record the It in Table 1.



- g) Compare the results obtained from (e) and (f).
- h) Calculate all branch currents I1 = ____ mA, I2 = ___ mA, and I3 = ___ mA and record the values in Table 1.
- i) Measure the branch circuit currents I1, I2, and I3, then record their values in the Table 1.
 - Connect the DMM as shown below for I1 measurement



Connect the DMM as shown below for I2 measurement



Connect the DMM as shown below for I3 measurement

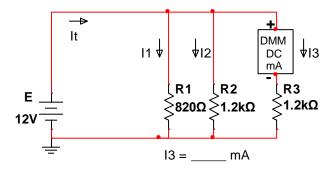
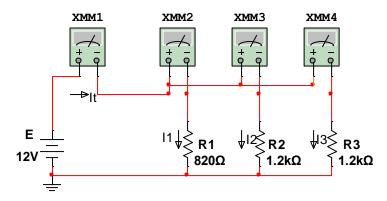


Table 1. Measured and calculated currents

	I1	12	I3 _t	lt
Calculated values				
Measured values				
Simulated values				

Part 2. Prepare a Multisim simulation circuit as shown below. Run the simulated circuit and record I1, I2, I3, and It.



a) Explain among the calculated, measured and simulated values.